

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
30-5004(4015)DIV2SERIAL NO.
09/912,652

LIST OF ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT
Vladimir Segal et al.FILING DATE
July 24, 2001GROUP
1742

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA	3,616,282	10-1971	Bodway			
AB	4,000,055	12-1976	Kumagai			
AC	4,020,222	4-1977	Kausche et al			
AD	5,994,181	11-1999	Hsieh et al			
AE						

FOREIGN PATENT DOCUMENTS

FORBIDDEN/RESTRICTED DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AF							
	AG							
	AH							
	AI							
	AJ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

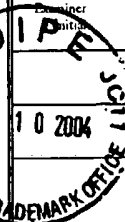
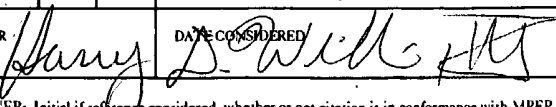
HW	AK	F. J. Humphreys et al., "Developing stable fine-grain microstructures by large strain deformation", Phil. Trans. R. Soc. Lond. A, June 15, 1999, Vol. 357 #1756, pp. 1663-1681.
HW	AL	S. Ferrasse et al., "Texture evolution during equal channel angular extrusion Part I. Effect of route, number of passes and initial texture", Materials Science and Engineering, Vol. 368, March 15, 2004, pp. 28-40.
HW	AM	V.M. Segal, "Equal channel angular extrusion: from macromechanics to structure formation", Materials Science & Engineering A271, November 1, 1999, pp. 322-333.
HW	AN	Rustan Z. Valiev et al., "SPD-Processed Ultra-Fine Grained Ti Materials for Medical Applications", Advanced Materials & Processes, December 2003, pp. 33-34.
HW	AR	Segal et al., "Plastic Working of Metals by Simple Shear", Russian Metall. Vol. 1, pp. 99-105, 1991.
HW	AS	N. Furukawa et al., "Microhardness Measurements and the Hall-Petch Relationship in an Al-Mg Alloy with Submicrometer Grain Size", Acta Mater. Vol. 44, No. 11, pp. 4619-4629, 1996.
HW	AT	Yoshinori Iwahashi et al., "Microstructural Characteristics of Ultrafine-Grained Aluminum Produced Using Equal-Channel Angular Pressing", Metallurgical and Materials Transactions, Vol. 29A, pp. 2245-2252, September 1998.

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

EV372455305

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 30-5004(4015)DIV 2		SERIAL NO. 09/912,652	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vladimir Segal et al.			
				FILING DATE July 24, 2001		GROUP 1742	
U.S. PATENT DOCUMENTS							
Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes No
	AF						
	AG						
	AH						
	AI						
	AJ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
HW	AK		S. Ferrasse et al., "ECAE Targets with Sub-Micron Grain Structures Improve Sputtering Performance and Cost-of-Ownership", Semiconductor Manufacturing, Vol. 4, Issue 10, October 2003, pp. 78-92.				
HW	AL		R.Z. Valiev et al., "Bulk Nanostructured materials from severe plastic deformation", Progress in Materials Science, Vol. 45, 2000, pp. 103-189.				
HW	AM		R. Z. Valiev et al., "Plastic Deformation of alloys with submicron-grained structure", Materials Science and Engineering, A137(1991) pp. 35-40.				
HW	AN		V. M. Segal et al., "Processes of Plastic Structure Formation", Science and Engineering, 1994, published in Russia, Chapters 1, 3 and 4, with Statement in Accordance with 37 CFR 1.98(a)(3)(i).				
	AR						
	AS						
	AT						
EXAMINER	DATE CONSIDERED						
	 9/14/04						
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

EV372455305